Selected Publications

N.I. Chkhalo, S. Künstner, V.N. Polkovnikov, N.N. Salashchenko, F. Schäfers, S.D. Starikov
High performance La/B_4C multilayer mirrors with C-barrier layers for the next generation lithography
Appl. Phys. Lett., in press (2012)

M.H Modi, S.K. Rai, M. Idir, F. Schäfers, G.S. Lodha
NbC/Si multilayer mirror for next generation EUV light sources
Optics Express **20/14**, 15114-20 (2012)

E.O. Filatova, I.V. Kozhevnikov, A.A. Sokolov, E.V. Ubyivovk, S. Yulin, M. Gorgoi, F. Schäfers
Soft X-Ray Reflectometry, Hard X-Ray Photoelectron Spectroscopy, and HRTEM investigations of the internal structure of TiO_2(Ti)/SiO_2/Si stacks
Sci. Technol. Adv. Mater. **13,** 015001, 1-12 (2012)

S. Grigorian, D. Tranchida, D. Ksenzov, F. Schäfers, H. Schönherr,. U. Pietsch
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European Polymer Journal **47**, 2189-96 (2011)

D. Ksenzov, Ch. Schlemper, A. Davtyan, S. Bajt, F. Schäfers, U. Pietsch
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E O Filatova, A A Sokolov, J.-M. André, F Schäfers and W Braun
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From Soft to Hard X-ray with a single grating monochromator

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S.S. Andreev A.D. Akhsakhalyan, M.A. Bibishkin, N.I. Chkhalo, S.V. Gaponov, S.A. Gusev, E.B. Kluenkov, K.A. Prokhorov, N.N. Salashchenko, F. Schäfers, S.Yu. Zev
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F. Schäfers, S. Yulin, T. Feigl, N. Kaiser
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